

Application No. Not Yet Assigned  
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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Application No. : Not Yet Assigned  
Applicants : **Chie ISHIKAWA et al.**  
Filed : Concurrently Herewith  
Title : **METHOD AND APPARATUS FOR  
INSPECTING SURFACE DEFECT**  
International Application : No. PCT/JP2004/015466  
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Customer Number : 28289

**MAIL STOP PCT**  
Commissioner for Patents  
P. O. Box 1450  
Alexandria, VA 22313-1450

**PRELIMINARY AMENDMENT**

Sir:

Prior to initial examination, please amend the above-identified patent application as follows:

**Amendments to the Claims** begin on page 2 of this paper.

**Amendments to the Abstract** begin on page 7 of this paper.

**Remarks** begin on page 8 of this paper.